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N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY			
VDS (V)	$R_{DS(on)}$ (Ω)	ID (A)[a]	Qg (Typ.)
30	0.033 at V_{GS} = 4.5 V	6.8	10 nC
	0.045 at V_{GS} = 2.5 V	6.8	

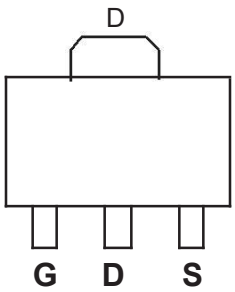
FEATURES

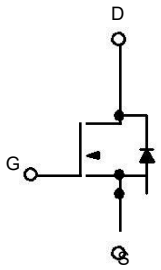
- **Halogen-free**
- TrenchFET® Power MOSFET

RoHS COMPLIANT

APPLICATIONS

- Load Switches for Portable Devices





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted				
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current (T_J = 150 °C)	T_C = 25 °C	I_D	6.8[a]	A
	T_C = 70 °C		6[a]	
	T_A = 25 °C		6.8[a, b, c]	
	T_A = 70 °C		6[a, b, c]	
Pulsed Drain Current		I_{DM}	30	
Continuous Source-Drain Diode Current	T_C = 25 °C	I_S	5.2	
	T_A = 25 °C		2.1[b, c]	
Maximum Power Dissipation	T_C = 25 °C	P_D	6.3	W
	T_C = 70 °C		4	
	T_A = 25 °C		2.5[b, c]	
	T_A = 70 °C		1.6[b, c]	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature)[e, f]			260	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient[a, c, d]	t ≤ 5 s	R_{thJA}	40	50	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	15	20	

Notes:

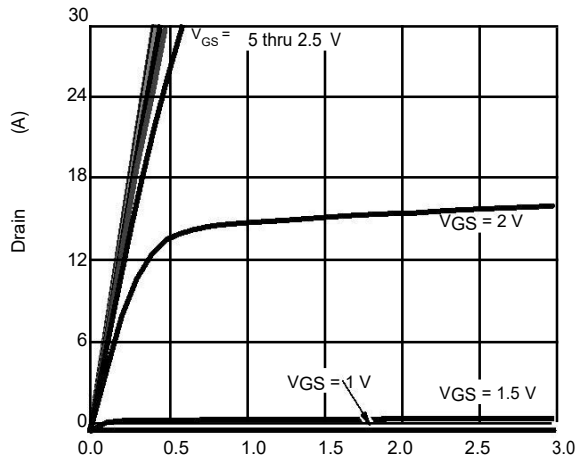
a. Package limited, T_C = 25 °C.
b. Surface Mounted on 1" x 1" FR4 board.
c. t = 10 s.
d. Maximum under Steady State conditions is 95 °C/W.
e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

SPECIFICATIONS T_J = 25 °C, unless otherwise noted						
Parameter	**Symbol**	**Test Conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
Static						
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0 V, I_D = 250 µA	30			V
V_{DS} Temperature Coefficient	V_{DS} /T_J	I_D = 250 µA		25		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$V_{GS(th)}$ /T_J			- 4.0		
Gate-Source Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS} , I_D = 250 µA	0.6		1.5	V
Gate-Source Leakage	I_{GSS}	V_{DS} = 0 V, V_{GS} = ± 20 V			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 30 V, V_{GS} = 0 V			1	µA
		V_{DS} = 30 V, V_{GS} = 0 V, T_J = 55 °C			10	
On-State Drain Current[a]	$I_{D(on)}$	V_{DS} ≥ 5 V, V_{GS} = 4.5 V	30			A
Drain-Source On-State Resistance[a]	$R_{DS(on)}$	V_{GS} = 4.5 V, I_D = 6.3 A		0.026	0.033	Ω
		V_{GS} = 2.5 V, I_D = 4.5 A		0.030	0.045	
Forward Transconductance[a]	g_{fs}	V_{DS} = 10 V, I_D = 6.3 A		45		S
Dynamic[b]						
Input Capacitance	C_{iss}	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz		1200		pF
Output Capacitance	C_{oss}			220		
Reverse Transfer Capacitance	C_{rss}			100		
Total Gate Charge	Q_g	V_{DS} = 10 V, V_{GS} = 10 V, I_D = 6.3 A		22	33	nC
		V_{DS} = 10 V, V_{GS} = 4.5 V, I_D = 6.3 A		10	15	
Gate-Source Charge	Q_{gs}			2.5		
Gate-Drain Charge	Q_{gd}			1.7		
Gate Resistance	R_g	f = 1 MHz		2.4		Ω
Turn-on Delay Time	$t_{d(on)}$	V_{DD} = 10 V, R_L = 1.5 Ω I_D 6.7 A, V_{GEN} = 4.5 V, R_g = 1 Ω		15	25	ns
Rise Time	t_r			10	15	
Turn-Off Delay Time	$t_{d(off)}$			35	55	
Fall Time	t_f			12	20	
Turn-on Delay Time	$t_{d(on)}$	V_{DD} = 10 V, R_L = 1.5 Ω I_D 6.7 A, V_{GEN} = 10 V, R_g = 1 Ω		10	15	
Rise Time	t_r			12	20	
Turn-Off Delay Time	$t_{d(off)}$			25	40	
Fall Time	t_f			10	15	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	T_C = 25 °C			5.2	A
Pulse Diode Forward Current	I_{SM}				30	
Body Diode Voltage	V_{SD}	I_S = 6.7 A, V_{GS} = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t_{rr}	I_F = 6.7 A, dI/dt = 100 A/µs, T_J = 25 °C		20	40	ns
Body Diode Reverse Recovery Charge	Q_{rr}			10	20	nC
Reverse Recovery Fall Time	t_a			10		ns
Reverse Recovery Rise Time	t_b			10		

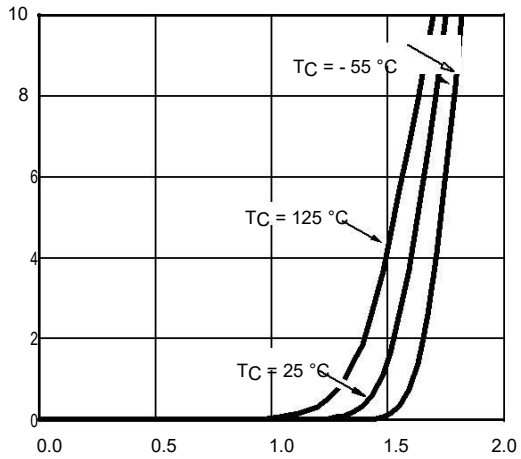
Notes:
a. Pulse test; pulse width ≤ 300 µs, duty cycle ≤ 2 %
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

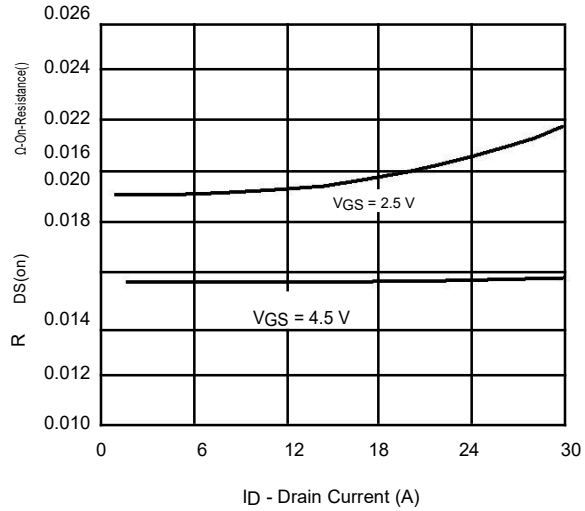
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

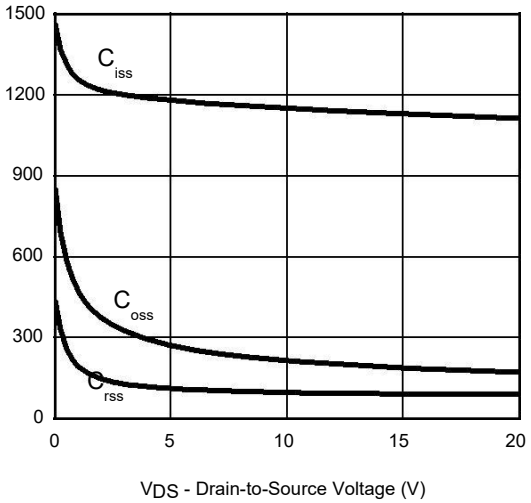


Output Characteristics



Transfer Characteristics





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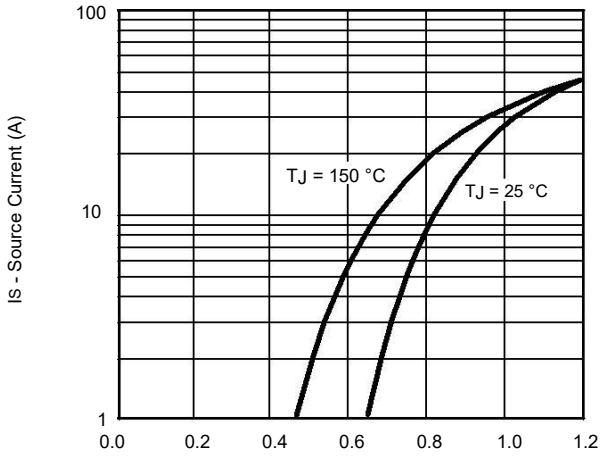
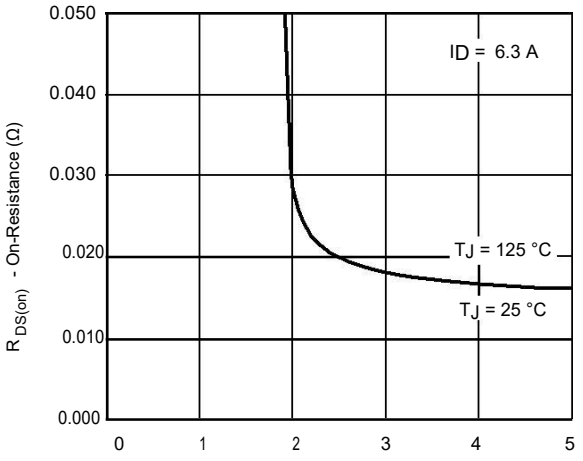
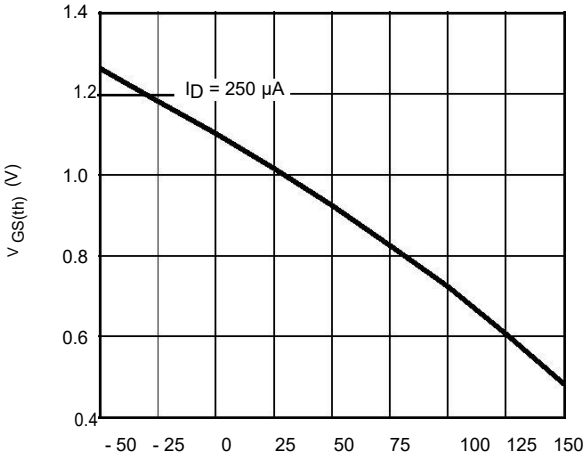


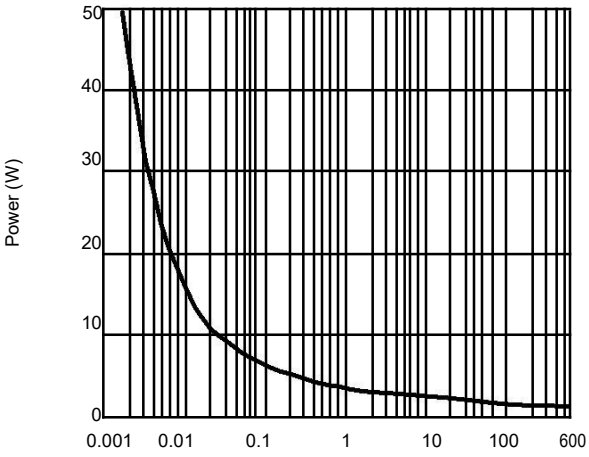
Source-Drain Diode Forward Voltage



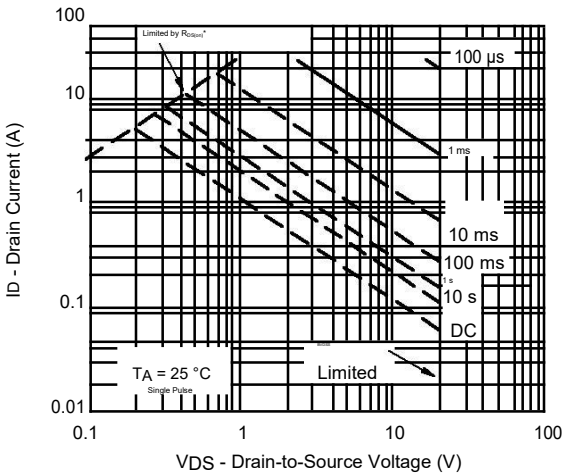
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

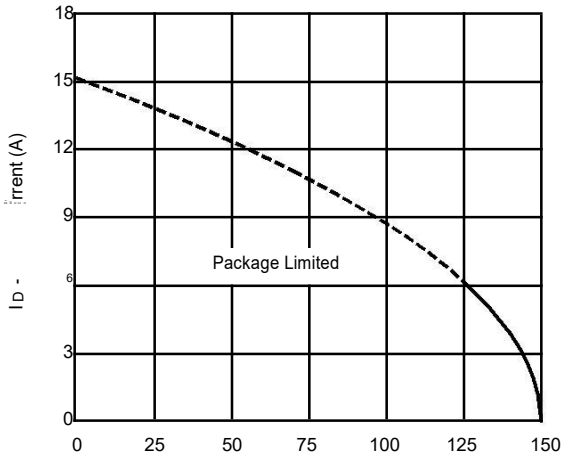


Single Pulse Power

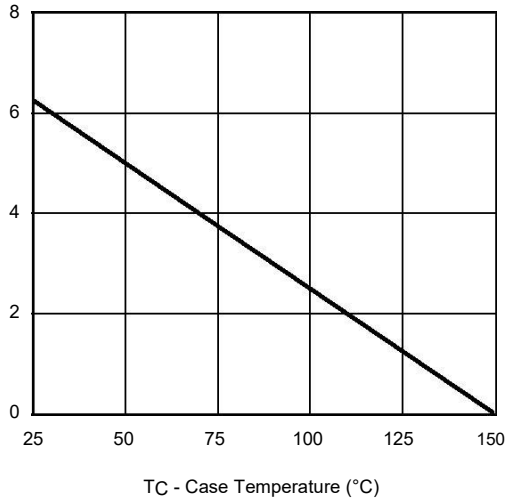


* VGS > minimum VGS at which RDS(on) is specified

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



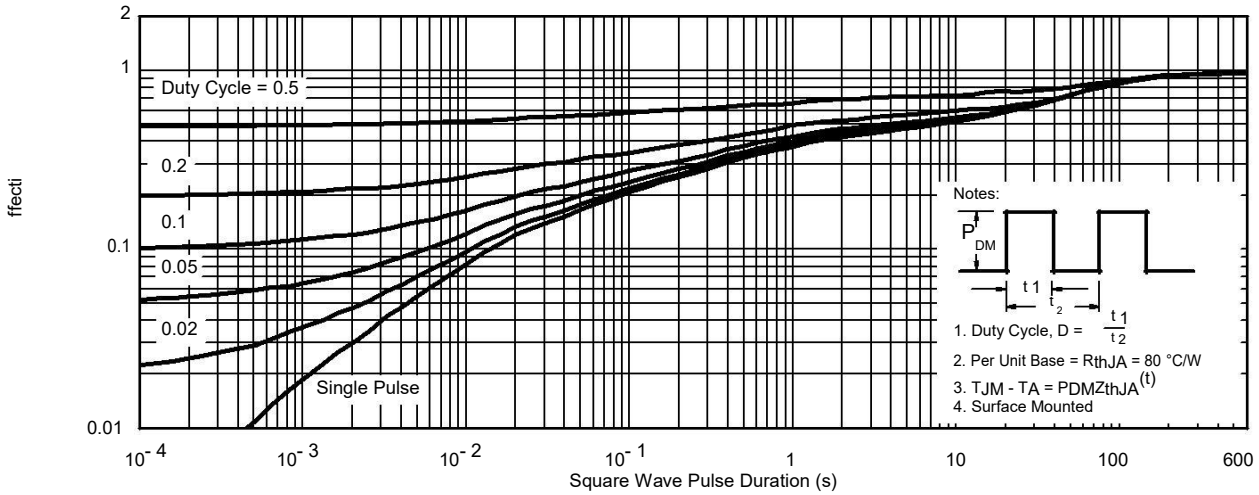
Current Derating*



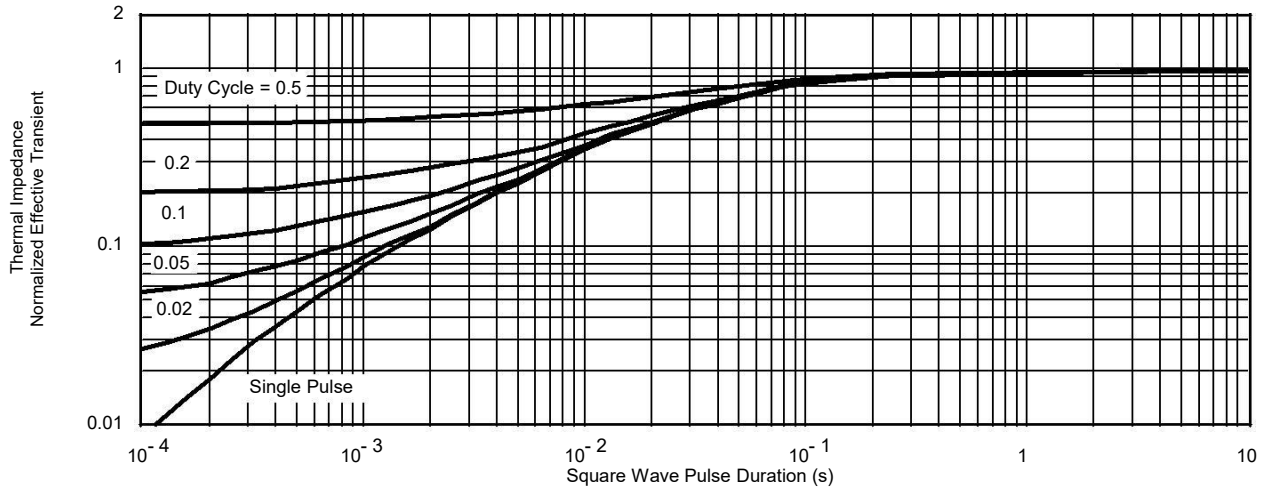
Power Derating

* The power dissipation PD is based on TJ(max) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

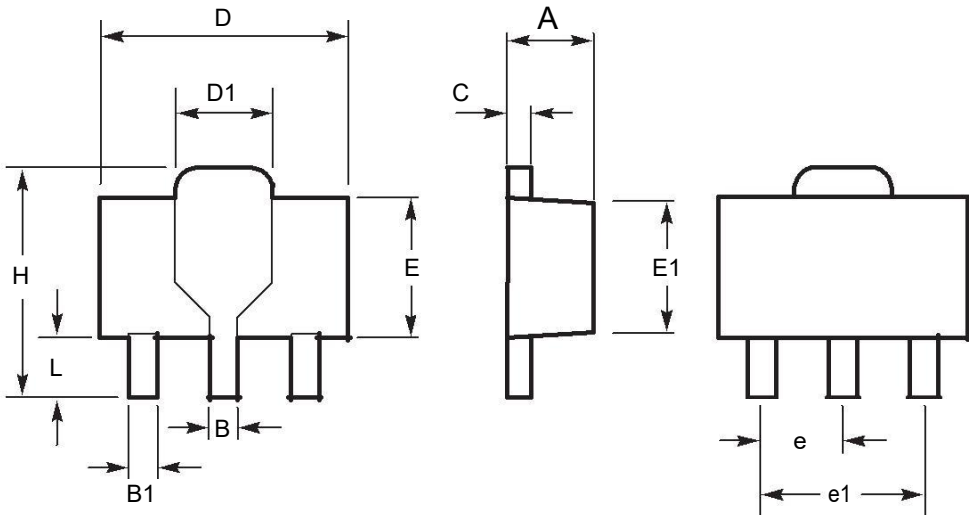


Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

Package outline - SOT89



DIM	Millimeters		Inches		DIM	Millimeters		Inches	
	Min	Max	Min	Max		Min	Max	Min	Max
A	1.40	1.60	0.550	0.630	E	2.29	2.60	0.090	0.102
B	0.44	0.56	0.017	0.022	E1	2.13	2.29	0.084	0.090
B1	0.36	0.48	0.014	0.019	e	1.50 BSC		0.059 BSC	
C	0.35	0.44	0.014	0.017	e1	3.00 BSC		0.118 BSC	
D	4.40	4.60	0.173	0.181	H	3.94	4.25	0.155	0.167
D1	1.62	1.83	0.064	0.072	L	0.89	1.20	0.035	0.047

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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